Application/Control No. Applicant(s)/Patent Under Reexamination 10/695,466 FONG ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Dah-Wei D. Yuan 1745 **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY * US-2005/0233214 10-2005 Marple et al. Α 429/221 US-2005/0136326 06-2005 Aisenbrey, Thomas 429/178 В С US-US-D US-Ε US-F US-G US-Н US-1 US-US-Κ US-L

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